

10042032  
10/25/01

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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10042032	FILING DATE 10/25/2001	CLASS 356	SUBCLASS 2154,1	GAU 2877	EXAMINER T. NGUYEN
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\*\*CONTINUING DATA VERIFIED:

THIS APPLICATION IS A DIV OF 09/158,362 09/22/1998

\*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN 9-258552 09/24/1997

JAPAN 10-264342 09/18/1998

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed 35 USC 119 conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 980615CD/LH
Verified and Acknowledged Examiners's initials		
TITLE : Apparatus for inspecting a substrate		
U.S. DEPT. OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)		

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
		Sheets Drawg.	Figa.Drawg.
Primary Examiner		Print Fig.	
PREPARED F R ISSUE		Application Examiner	
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TERMINAL		DISCLAIMER	

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